

100V N-Channel Enhancement Mode MOSFET

Description

The AP300N10T uses advanced **APM-SGT₁₁** technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 100V$ $I_D = 300A$

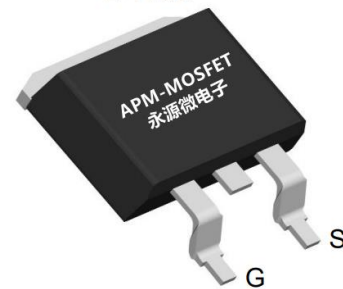
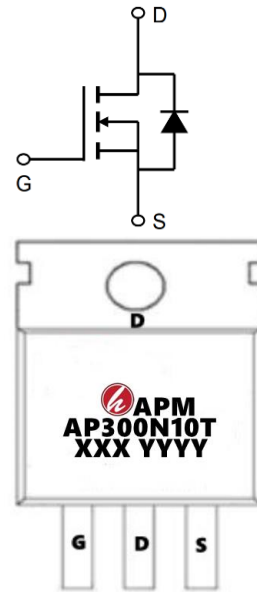
$R_{DS(ON)} < 2.2m\Omega$ @ $V_{GS}=10V$ (Type: **1.6m Ω**)

Application

DC/DC Converter

LED Backlighting

Power Management Switches



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP300N10T	TO-263-3L	AP300N10T XXX YYYY	800

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	100	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D@T_C=25^\circ\text{C}$	Continuous Drain Current, V_{GS} @ 10V	30	A
$I_D@T_C=100^\circ\text{C}$	Continuous Drain Current, V_{GS} @ 10V	210	A
IDM	Pulsed Drain Current	1248	A
EAS	Single Pulse Avalanche Energy	2340	mJ
IAS	Avalanche Current	53.4	A
$P_D@T_C=25^\circ\text{C}$	Total Power Dissipation ⁴	390.6	W
TSTG	Storage Temperature Range	-55 to 175	$^\circ\text{C}$
T_J	Operating Junction Temperature Range	-55 to 175	$^\circ\text{C}$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient	0.13	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance Junction-Case	40	$^\circ\text{C/W}$

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Electrical Characteristics (T_C=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _D = 250μA	100	111	-	V
I _{GSS}	Gate-body Leakage current	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA
I _{DSS}	Zero Gate Voltage Drain Current T _J =25°C	V _{DS} = 100V, V _{GS} = 0V	-	-	1	μA
I _{DSS}	Zero Gate Voltage Drain Current T _J =100°C		-	-	100	
V _{GS(th)}	Gate-Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	2.0	3.0	4.0	V
R _{DS(on)}	Drain-Source on-Resistance ⁴	V _{GS} = 10V, I _D = 20A	-	1.6	2.2	mΩ
g _{fs}	Forward Transconductance ⁴	V _{DS} = 10V, I _D = 20A	-	84	-	S
C _{iss}	Input Capacitance	V _{DS} = 50V, V _{GS} = 0V, f = 1MHz	-	14300	-	pF
C _{oss}	Output Capacitance		-	2120	-	
C _{rss}	Reverse Transfer Capacitance		-	50	-	
R _g	Gate Resistance	f=1MHz	-	2.8	-	Ω
Q _g	Total Gate Charge	V _{GS} = 10V, V _{DS} = 50V, I _D = 20A	-	250	-	nC
Q _{gs}	Gate-Source Charge		-	53	-	
Q _{gd}	Gate-Drain Charge		-	77	-	
t _{d(on)}	Turn-on Delay Time	V _{GS} = 10V, V _{DD} = 50V, R _G = 3Ω, I _D = 20A	-	41	-	ns
t _r	Rise Time		-	88	-	
t _{d(off)}	Turn-off Delay Time		-	163	-	
t _f	Fall Time		-	98	-	
t _{rr}	Body Diode Reverse Recovery Time	I _F = 20A, di/dt = 100A/μs	-	106	-	ns
Q _{rr}	Body Diode Reverse Recovery Charge		-	245	-	nC
V _{SD}	Diode Forward Voltage ⁴	I _S = 20A, V _{GS} = 0V	-	-	1.2	V
I _S	Continuous Source Current T _C =25°C		-	-	312	A

Notes:

- 1、 The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、 The EAS data shows Max. rating . The test condition is V_{DD}=90V, V_{GS}=10V, L=1.0mH, I_{AS}=50A
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

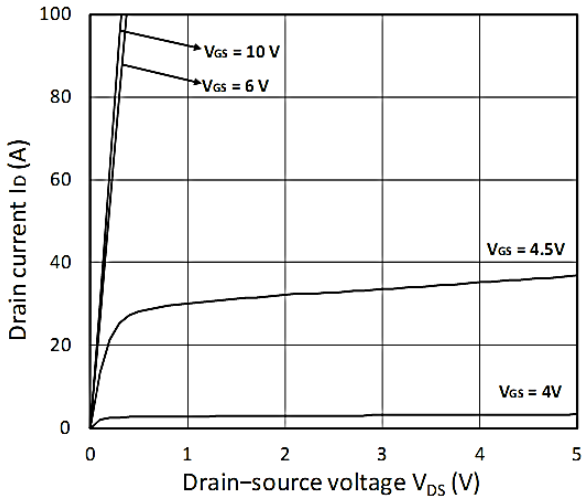


Figure 1. Output Characteristics

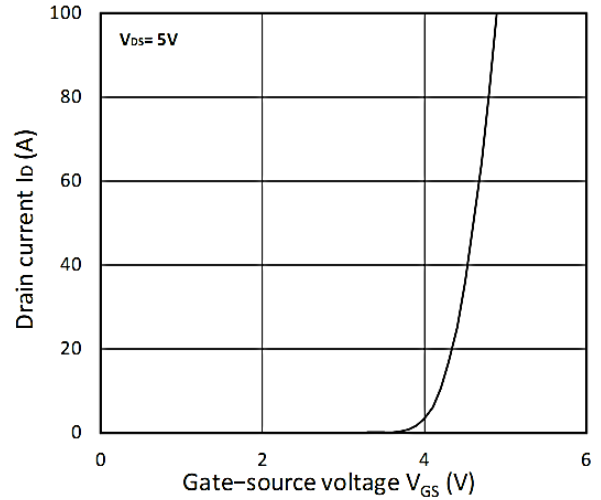


Figure 2. Transfer Characteristics

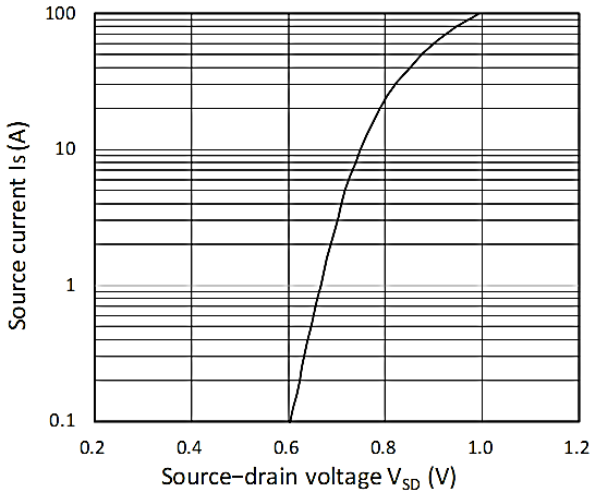


Figure 3. Forward Characteristics of Reverse

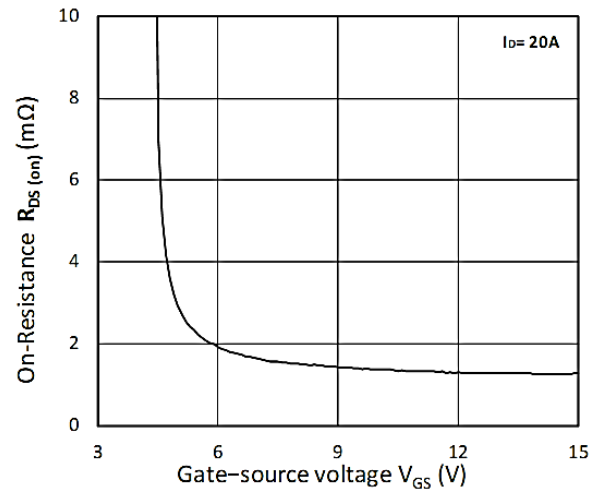


Figure 4. RDS(ON) vs. VGS

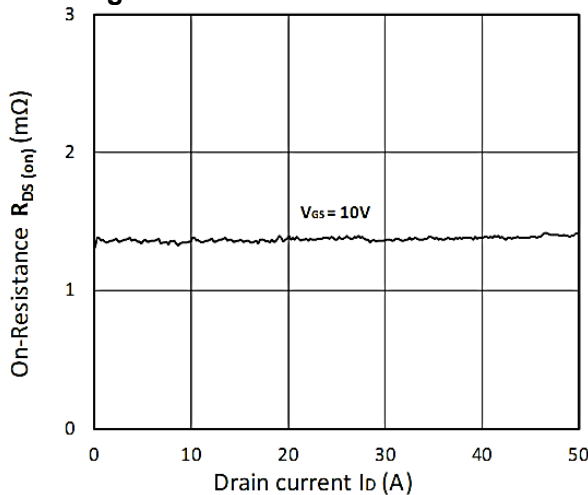


Figure 5. RDS(ON) vs. ID

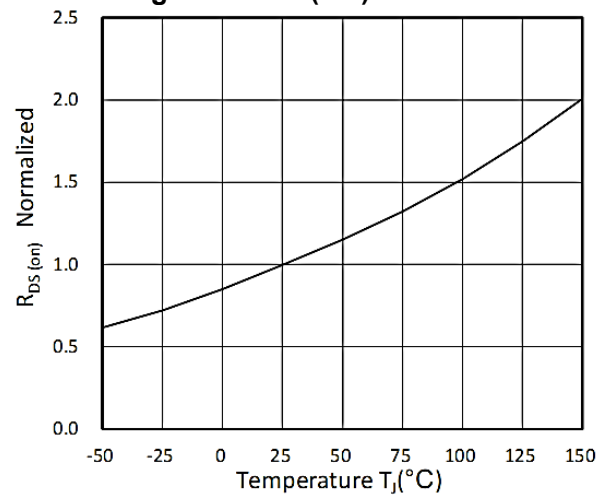


Figure 6. Normalized R DS(on) vs. Temperature

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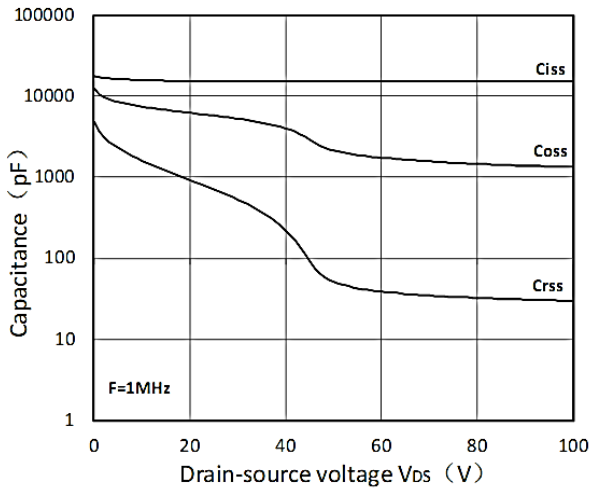


Figure 7. Capacitance Characteristics

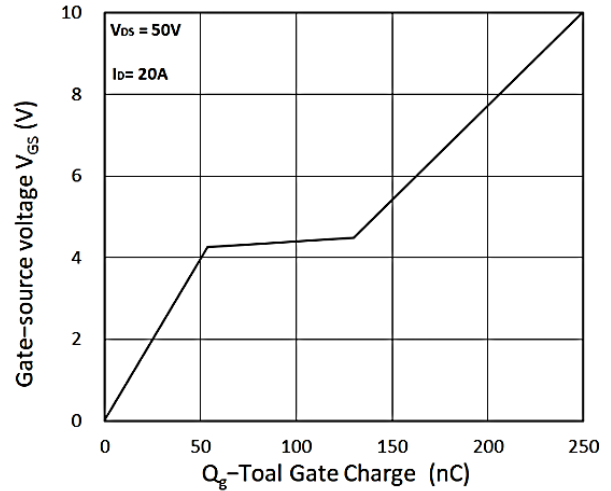


Figure 8. Gate Charge Characteristics

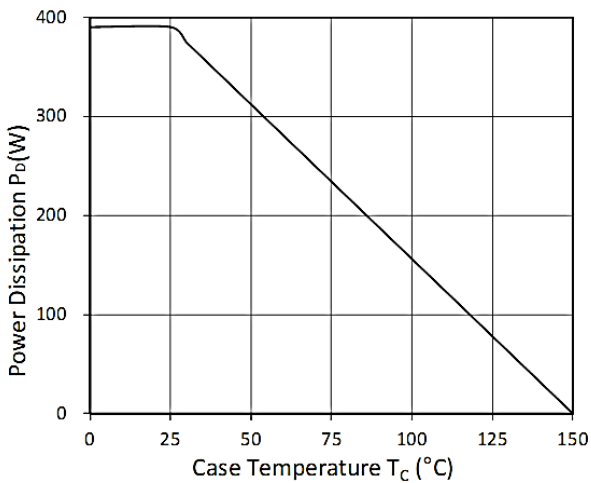


Figure 9. Power Dissipation

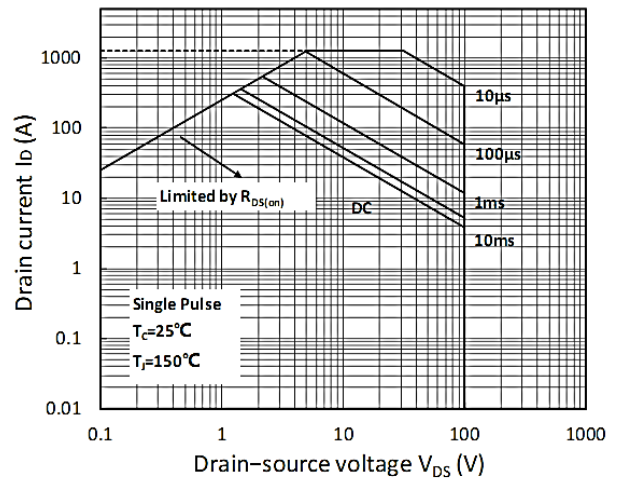


Figure 10. Safe Operating Area

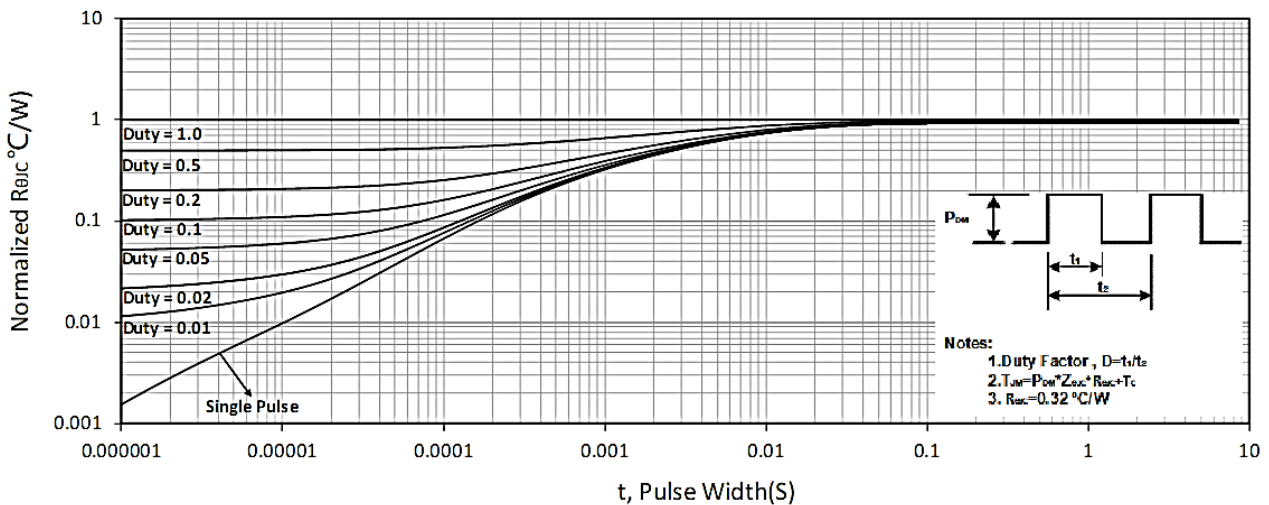
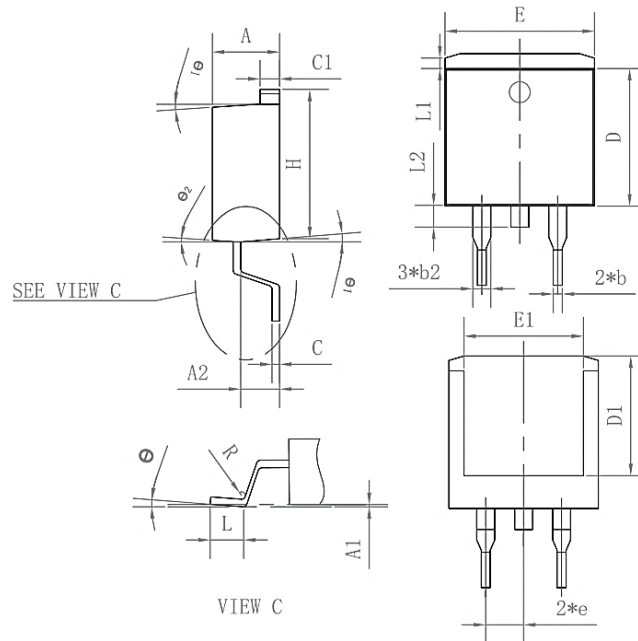


Figure 11. Normalized Maximum Transient Thermal Impedance

Package Mechanical Data-TO-263-3L-SLK



Symbol	Common		
	mm		
	Mim	Nom	Max
A	4.35	4.47	4.60
A1	0.09	0.10	0.11
A2	2.30	2.40	2.70
b	0.70	0.80	1.00
b2	1.25	1.36	1.50
C	0.45	0.50	0.65
C1	1.29	1.30	9.40
D	9.10	9.20	9.30
D1	7.90	8.00	8.10
E	9.85	10.00	10.20
E1	7.90	8.00	8.10
H	15.30	15.50	15.70
e	-	2.54	-
L	2.34	2.54	2.74
L1	1.00	1.10	1.20
L2	1.30	1.40	1.50
R	0.24	0.25	0.26
theta	0°	4°	8°
theta1	4°	7°	10°
theta2	0°	3°	6°

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Edition	Date	Change
Rve1.0	2022/5/5	Initial release

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